LMA1008
8 x 8-bit Multiplier-Accumulator

FEATURES

- 20 ns Multiply-Accumulate Time
- Low Power CMOS Technology
- Replaces Raytheon TMC2208
- Two's Complement or Unsigned Operands
- Accumulator Performs Preload, Accumulate, and Subtract
- Three-State Outputs
- DECC SMD No. 5962-90708
- Available 100% Screened to MIL-STD-883, Class B
- Package Styles Available:
  - 48-pin Plastic DIP
  - 48-pin Sidebraze, Hermetic DIP
  - 68-pin Plastic LCC, J-Lead

DESCRIPTION

The **LMA1008** is a high-speed, low power 8-bit multiplier-accumulators. It is pin-for-pin equivalent to the Raytheon TMC2208 multiplier-accumulators. Full ambient temperature range operation is achieved by the use of advanced CMOS technology.

The LMA1008 produces the 16-bit product of two 8-bit numbers. The results of a series of multiplications may be accumulated to form the sum of products. Accumulation is performed to 19-bit precision with the multiplier product sign extended as appropriate.

Data present at the A and B input registers is latched on the rising edges of CLK A and CLK B respectively. RND, TC, ACC, and SUB controls are latched on the rising edge of the logical OR of CLK A and CLK B. TC specifies the input as two's complement (TC HIGH) or unsigned magnitude (TC LOW). RND, when HIGH, adds '1' to the most significant bit position of the least significant half of the product. Subsequent truncation of the 8 least significant bits produces a result correctly rounded to 8-bit precision.

The ACC and SUB inputs control accumulator operation. ACC HIGH results in addition of the multiplier product and the accumulator contents, with the result stored in the accumulator register on the rising edge of CLK R. ACC and SUB HIGH results in subtraction of the accumulator contents from the multiplier product, with the result stored in the accumulator register. With ACC LOW, no accumulation occurs and the next product is loaded directly into the accumulator register.

The LMA1008 output register (accumulator register) is divided into three independently controlled sections. The least significant result (LSR) and most significant result (MSR) registers are 8 bits in length. The extended result register (XTR) is 3 bits long.

Each output register has an independent output enable control. In addition to providing control of the three-state output buffers, when $\overline{OEX}$, $\overline{OEM}$, or $\overline{OEL}$ are HIGH and PREL is HIGH, data can be preloaded via the bidirectional output pins into the respective output registers. Data present on the output pins is latched on the rising edge of CLK R. The interrelation of PREL and the enable controls is summarized in Table 1.

LMA1008 Block Diagram

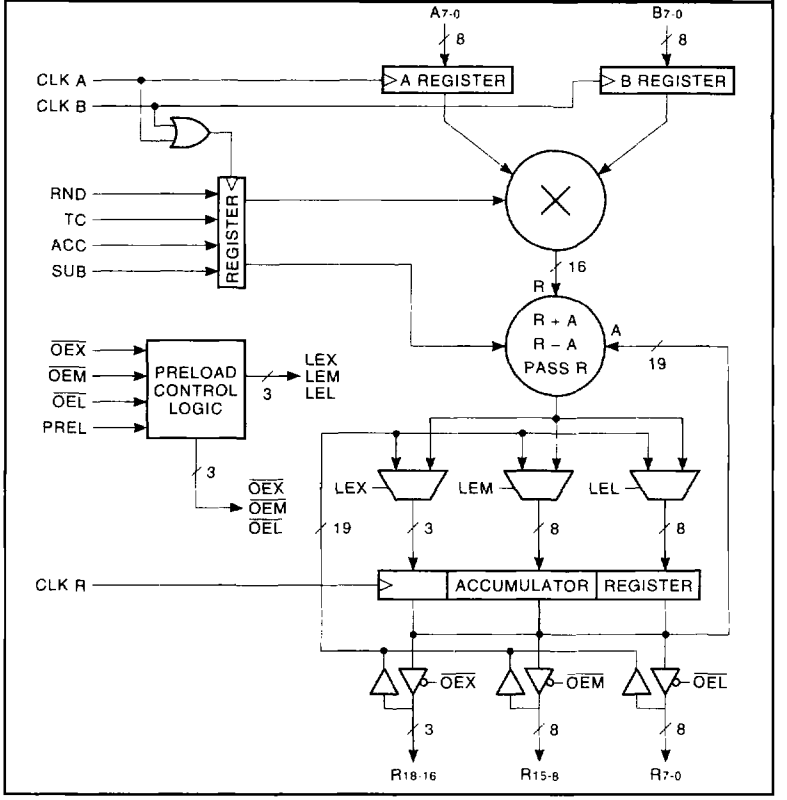

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TABLE 1. PRELOAD TRUTH TABLE

PREL	$\overline{OEX}$	$\overline{OEM}$	$\overline{OEL}$	XTR	MSR	LSR
L	L	L	L	OUT	OUT	OUT
L	L	L	H	OUT	OUT	Z
L	L	H	L	OUT	Z	OUT
L	L	H	H	OUT	Z	Z
L	H	L	L	Z	OUT	OUT
L	H	L	H	Z	OUT	Z
L	H	H	L	Z	Z	OUT
L	H	H	H	Z	Z	Z
H	L	L	L	Z	Z	Z
H	L	L	H	Z	Z	PREL
H	L	H	L	Z	PREL	Z
H	L	H	H	Z	PREL	PREL
H	H	L	L	PREL	Z	Z
H	H	L	H	PREL	Z	PREL
H	H	H	L	PREL	PREL	Z
H	H	H	H	PREL	PREL	PREL

PREL = Preload data to appropriate register
OUT = Register available on output pins
Z = High impedance state

FIGURE 1A. INPUT FORMATS

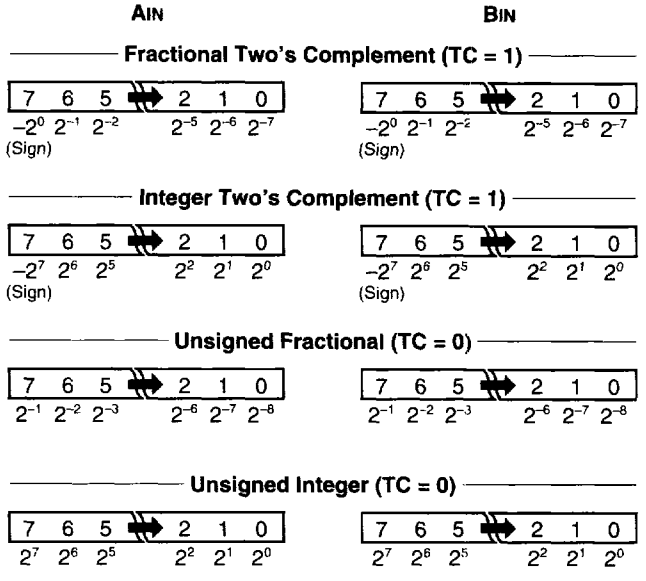
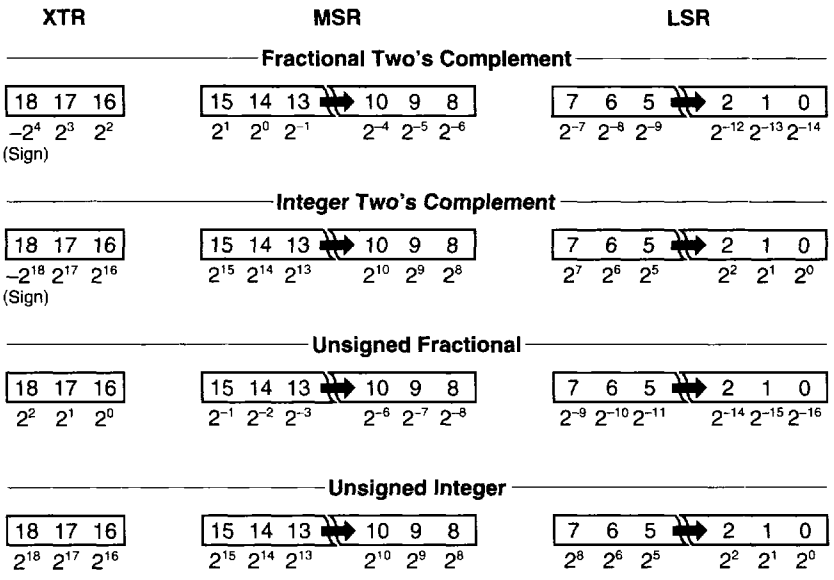


FIGURE 1B. OUTPUT FORMATS



Maximum Ratings *Above which useful life may be impaired (Notes 1, 2, 3, 8)*

Storage temperature	–65°C to +150°C
Operating ambient temperature	–55°C to +125°C
V_{CC} supply voltage with respect to ground	–0.5 V to +7.0 V
Input signal with respect to ground	–3.0 V to +7.0 V
Signal applied to high impedance output	–3.0 V to +7.0 V
Output current into low outputs	25 mA
Latchup current	> 400 mA

Operating Conditions *To meet specified electrical and switching characteristics*

Mode	Temperature Range (Ambient)	Supply Voltage
Active Operation, Commercial	0°C to +70°C	4.75 V ≤ V_{CC} ≤ 5.25 V
Active Operation, Military	–55°C to +125°C	4.50 V ≤ V_{CC} ≤ 5.50 V

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Electrical Characteristics *Over Operating Conditions (Note 4)*

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
V_{OH}	Output High Voltage	V_{CC} = Min., I_{OH} = –2.0 mA	2.4			V
V_{OL}	Output Low Voltage	V_{CC} = Min., I_{OL} = 8.0 mA			0.5	V
V_{IH}	Input High Voltage		2.0		V_{CC}	V
V_{IL}	Input Low Voltage	(Note 3)	0.0		0.8	V
I_{IX}	Input Current	Ground ≤ V_{IN} ≤ V_{CC} (Note 12)			±20	µA
I_{OZ}	Output Leakage Current	Ground ≤ V_{OUT} ≤ V_{CC} (Note 12)			±20	µA
I_{CC1}	V_{CC} Current, Dynamic	(Notes 5, 6)		12	25	mA
I_{CC2}	V_{CC} Current, Quiescent	(Note 7)			1.0	mA

SWITCHING CHARACTERISTICS

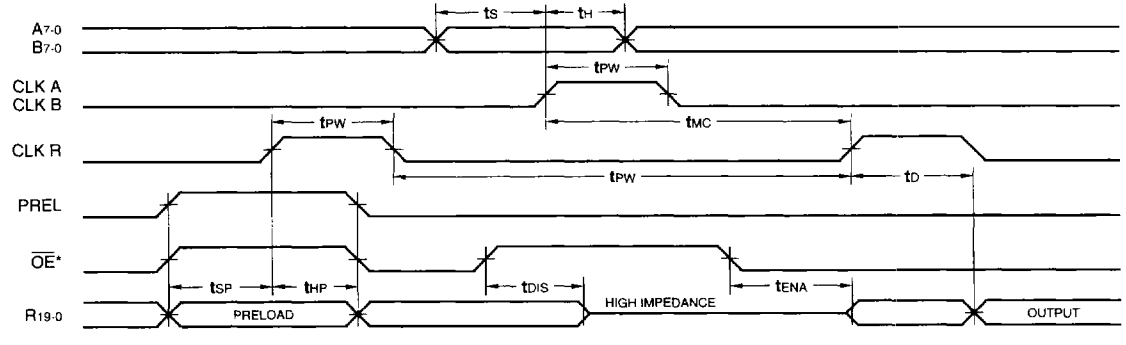
COMMERCIAL OPERATING RANGE (0°C to +70°C) *Notes 9, 10 (ns)*

		LMA1008–			
		40		20	
Symbol	Parameter	Min	Max	Min	Max
t_{MC}	Clocked Multiply Time		40		20
t_{PW}	Clock Pulse Width	15		8	
t_S	Input Register Setup Time	10		10	
t_H	Input Register Hold Time	0		0	
t_{SP}	Preload Setup Time	12		12	
t_{HP}	Preload Hold Time	2		2	
t_D	Output Delay		23		18
t_{ENA}	Three-State Output Enable Delay (Note 11)		19		18
t_{DIS}	Three-State Output Disable Delay (Note 11)		16		16

MILITARY OPERATING RANGE (–55°C to +125°C) *Notes 9, 10 (ns)*

		LMA1008–			
		50		25	
Symbol	Parameter	Min	Max	Min	Max
t_{MC}	Clocked Multiply Time		50		25
t_{PW}	Clock Pulse Width	15		10	
t_S	Input Register Setup Time	11		11	
t_H	Input Register Hold Time	2		2	
t_{SP}	Preload Setup Time	13		13	
t_{HP}	Preload Hold Time	2		2	
t_D	Output Delay		25		20
t_{ENA}	Three-State Output Enable Delay (Note 11)		21		20
t_{DIS}	Three-State Output Disable Delay (Note 11)		18		18

SWITCHING WAVEFORMS



*includes $\overline{OEX}$, $\overline{OEM}$, $\overline{OEL}$

NOTES

1. Maximum Ratings indicate stress specifications only. Functional operation of these products at values beyond those indicated in the Operating Conditions table is not implied. Exposure to maximum rating conditions for extended periods may affect reliability.

2. The products described by this specification include internal circuitry designed to protect the chip from damaging substrate injection currents and accumulations of static charge. Nevertheless, conventional precautions should be observed during storage, handling, and use of these circuits in order to avoid exposure to excessive electrical stress values.

3. This device provides hard clamping of transient undershoot and overshoot. Input levels below ground or above V_{CC} will be clamped beginning at –0.6 V and V_{CC} + 0.6 V. The device can withstand indefinite operation with inputs in the range of –0.5 V to +7.0 V. Device operation will not be adversely affected, however, input current levels will be well in excess of 100 mA.

4. Actual test conditions may vary from those designated but operation is guaranteed as specified.

5. Supply current for a given application can be accurately approximated by:

$$\frac{NCV^2F}{4}$$

where

N = total number of device outputs
C = capacitive load per output
V = supply voltage
F = clock frequency

6. Tested with all outputs changing every cycle and no load, at a 5 MHz clock rate.

7. Tested with all inputs within 0.1 V of V_{CC} or Ground, no load.

8. These parameters are guaranteed but not 100% tested.

9. AC specifications are tested with input transition times less than 3 ns, output reference levels of 1.5 V (except t_{DIS} test), and input levels of nominally 0 to 3.0 V. Output loading may be a resistive divider which provides for specified I_{OH} and I_{OL} at an output voltage of V_{OH} min and V_{OL} max respectively. Alternatively, a diode bridge with upper and lower current sources of I_{OH} and I_{OL} respectively, and a balancing voltage of 1.5 V may be used. Parasitic capacitance is 30 pF minimum, and may be distributed.

This device has high-speed outputs capable of large instantaneous current pulses and fast turn-on/turn-off times. As a result, care must be exercised in the testing of this device. The following measures are recommended:

a. A 0.1 µF ceramic capacitor should be installed between V_{CC} and Ground leads as close to the Device Under Test (DUT) as possible. Similar capacitors should be installed between device V_{CC} and the tester common, and device ground and tester common.

b. Ground and V_{CC} supply planes must be brought directly to the DUT socket or contactor fingers.

c. Input voltages should be adjusted to compensate for inductive ground and V_{CC} noise to maintain required DUT input levels relative to the DUT ground pin.

10. Each parameter is shown as a minimum or maximum value. Input requirements are specified from the point of view of the external system driving the chip. Setup time, for example, is specified as a minimum since the external system must supply at least that much time to meet the worst-case requirements of all parts. Responses from the internal circuitry are specified from the point of view of the device. Output delay, for example, is specified as a maximum since worst-case operation of any device always provides data within that time.

11. For the t_{ENA} test, the transition is measured to the 1.5 V crossing point with datasheet loads. For the t_{DIS} test, the transition is measured to the ±200mV level from the measured steady-state output voltage with ±10mA loads. The balancing voltage, V_{TH}, is set at 3.5 V for Z-to-0 and 0-to-Z tests, and set at 0 V for Z-to-1 and 1-to-Z tests.

12. These parameters are only tested at the high temperature extreme, which is the worst case for leakage current.

FIGURE A. OUTPUT LOADING CIRCUIT

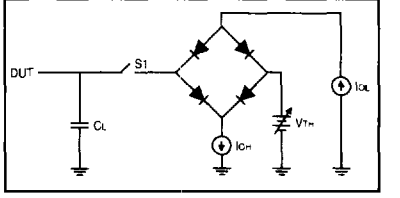
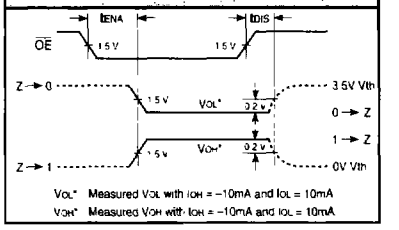


FIGURE B. THRESHOLD LEVELS



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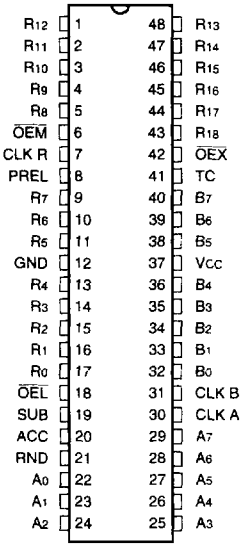
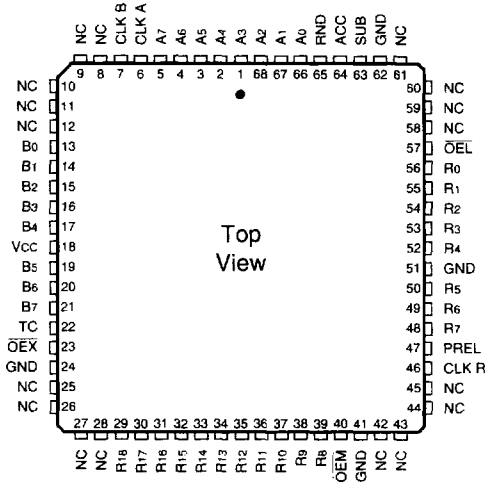
LMA1008 — ORDERING INFORMATION

48-pin



68-pin



Speed	Sidebraze Hermetic DIP (D6)	Plastic DIP (P5)	Plastic J-Lead Chip Carrier (J2)
	0°C to +70°C — Commercial Screening		
40 ns		LMA1008PC40	LMA1008JC40
20 ns		LMA1008PC20	LMA1008JC20
	–55°C to +125°C — Commercial Screening		
50 ns			
25 ns			
	–55°C to +125°C — MIL-STD-883 Compliant		
50 ns	LMA1008DMB50		
25 ns	LMA1008DMB25		